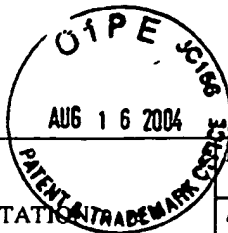


Form PTO-1449 (Reproduced)				Docket Number (Optional) <b>130894-2 60SD</b>		Application Number <b>1016995024</b>	
<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b> <i>(Use several sheets if necessary)</i>				Applicant <b>GENERAL ELECTRIC COMPANY</b>			
				Filing Date <b>October 31, 2003</b>		Group Art Unit	
<b>U. S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
J	6,273,948	2001-08-14	Porowski <i>et al.</i>	117	077		
	2,941,241	1960-06-01	Strong	425	077		
	4,523,478	1985-06-18	Zacharias	073	861		
	6,375,446	2002-04-23	Leonelli	425	077		
N	2003/0140845	2003-07-31	D'Evelyn <i>et al.</i>	117	008		
	5236674	1993-08-1	Frushour	422	241		
<b>FOREIGN PATENT DOCUMENTS</b>							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION		
					YES	NO	
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
EXAMINER	DATE CONSIDERED						
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INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)				Applicant GENERAL ELECTRIC COMPANY			
				Filing Date 10/31/2003			
Group Art Unit 1765							
U. S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	US2003/140845	07/31/03	D'Evelyn et al.				
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
						YES	NO
	EP0220462	05/06/87	Europe				
	EP0157393	10/09/85	Europe				
	GB922619	04/03/63	Great Britian				
	FR1306951	10/19/62	France				
	WO 01/36080	05/25/01	World				
	EP0152726	08/28/85	Europe				
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
	Hanser A D, et al.: "Growth, doping and characterization of epitaxial thin films and patterned structures of AlN, GaN, and Al <sub>x</sub> Ga <sub>1-x</sub> N"; XP004364890						
	Lawniczak-Jablonska K. et al.: "Polarization dependent x-ray absorption studies of the chemical bonds anisotropy in wurtzite GaN grown at different conditions"; XP004304294						
EXAMINER			DATE CONSIDERED 11/14/05				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							